

## N-Channel Super Junction Power MOSFET IV

### General Description

The series of devices use advanced trench gate super junction technology and design to provide excellent  $R_{DS(ON)}$  with low gate charge. This super junction MOSFET fits the industry's AC-DC SMPS requirements for PFC, AC/DC power conversion, and industrial power applications.

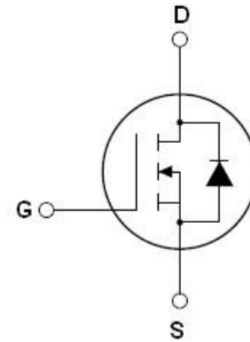
### Features

- Optimized body diode reverse recovery performance
- Low on-resistance and low conduction losses
- Small package
- Ultra Low Gate Charge cause lower driving requirements
- 100% Avalanche Tested
- ROHS compliant

### Application

- Power factor correction (PFC)
- Switched mode power supplies(SMPS)
- Uninterruptible Power Supply (UPS)
- LLC Half-bridge

$V_{DS\ min@T_{jmax}}$	710	V
$R_{DS(ON)TYP}$	60	mΩ
$I_D$	45	A
Qg	65	nC



Schematic diagram

✧ Intrinsic fast-recovery body diode

### Package Marking And Ordering Information

Device	Device Package	Marking
NCE65NF068D	TO-263	NCE65NF068D



Table 1. Absolute Maximum Ratings ( $T_J=25^\circ\text{C}$ )

TO-263

Parameter	Symbol	Value	Unit
Drain-Source Voltage ( $V_{GS}=0V$ )	$V_{DS}$	650	V
Gate-Source Voltage ( $V_{DS}=0V$ ) AC ( $f>1\text{ Hz}$ )	$V_{GS}$	$\pm 30$	V
Gate-Source Voltage ( $V_{DS}=0V$ ) DC	$V_{GS}$	$\pm 20$	V
Continuous Drain Current at $T_c=25^\circ\text{C}$	$I_{D(DC)}$	45	A
Continuous Drain Current at $T_c=100^\circ\text{C}$	$I_{D(DC)}$	31.5	A
Pulsed drain current (Note 1)	$I_{DM(pluse)}$	135	A
Maximum Power Dissipation( $T_c=25^\circ\text{C}$ )	$P_D$	371	W
Derate above $25^\circ\text{C}$		2.47	W/ $^\circ\text{C}$
Single pulse avalanche energy (Note 2)	$E_{AS}$	400	mJ
Avalanche current(Note 1)	$I_{AS}$	10	A
Repetitive Avalanche energy, $t_{AR}$ limited by $T_{jmax}$ (Note 1)	$E_{AR}$	0.9	mJ
Drain Source voltage slope, $V_{DS} \leq 480\text{ V}$ ,	$dv/dt$	50	V/ns
Reverse diode $dv/dt$ , $V_{DS} \leq 480\text{ V}, I_{SD} < I_D$	$dv/dt$	50	V/ns
Operating Junction and Storage Temperature Range	$T_J, T_{STG}$	-55...+175	$^\circ\text{C}$

\* limited by maximum junction temperature

**Table 2. Thermal Characteristic**

Parameter	Symbol	Value	Unit
Thermal Resistance, Junction-to-Case (Maximum)	$R_{thJC}$	0.40	$^{\circ}\text{C}/\text{W}$
Thermal Resistance, Junction-to-Ambient (Maximum)	$R_{thJA}$	62	$^{\circ}\text{C}/\text{W}$

**Table 3. Electrical Characteristics ( $T_J=25^{\circ}\text{C}$  unless otherwise noted)**

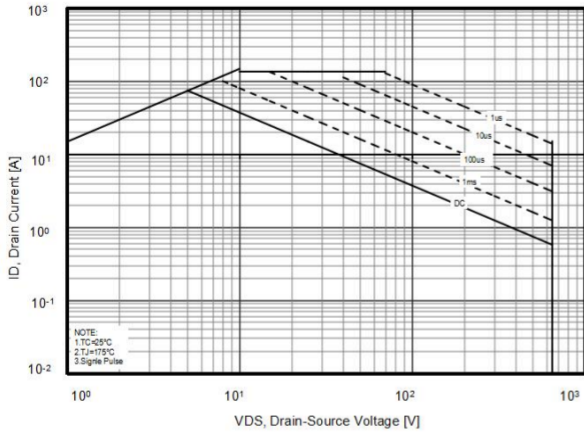
Parameter	Symbol	Condition	Min	Typ	Max	Unit
<b>On/off states</b>						
Drain-Source Breakdown Voltage	$BV_{DSS}$	$V_{GS}=0\text{V}, I_D=1\text{mA}$	650			V
Zero Gate Voltage Drain Current( $T_c=25^{\circ}\text{C}$ )	$I_{DSS}$	$V_{DS}=650\text{V}, V_{GS}=0\text{V}$			10	$\mu\text{A}$
Zero Gate Voltage Drain Current( $T_c=125^{\circ}\text{C}$ )	$I_{DSS}$	$V_{DS}=650\text{V}, V_{GS}=0\text{V}$			400	$\mu\text{A}$
Gate-Body Leakage Current	$I_{GSS}$	$V_{GS}=\pm 20\text{V}, V_{DS}=0\text{V}$			$\pm 100$	nA
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}, I_D=500\mu\text{A}$	3.5	4.2	5	V
Drain-Source On-State Resistance	$R_{DS(on)}$	$V_{GS}=10\text{V}, I_D=23\text{A}$		60	68	m $\Omega$
<b>Dynamic Characteristics</b>						
Input Capacitance	$C_{iss}$	$V_{DS}=50\text{V}, V_{GS}=0\text{V},$ $F=1.0\text{MHz}$		3900	4400	pF
Output Capacitance	$C_{oss}$			132		pF
Reverse Transfer Capacitance	$C_{rss}$			14		pF
Total Gate Charge	$Q_g$	$V_{DS}=480\text{V}, I_D=23\text{A},$ $V_{GS}=10\text{V}$		65	70	nC
Gate-Source Charge	$Q_{gs}$			21		nC
Gate-Drain Charge	$Q_{gd}$			17		nC
Gate plateau voltage	$V_{gp}$			6.5		V
Intrinsic gate resistance	$R_G$	$f = 1 \text{ MHz open drain}$		3		$\Omega$
<b>Switching times</b>						
Turn-on Delay Time	$t_{d(on)}$	$V_{DD}=380\text{V}, I_D=23\text{A},$ $R_G=1.7\Omega, V_{GS}=10\text{V}$		42		nS
Turn-on Rise Time	$t_r$			14		nS
Turn-Off Delay Time	$t_{d(off)}$			90		nS
Turn-Off Fall Time	$t_f$			12		nS
<b>Source- Drain Diode Characteristics</b>						
Source-drain current(Body Diode)	$I_{SD}$	$T_C=25^{\circ}\text{C}$			45	A
Pulsed Source-drain current(Body Diode)	$I_{SDM}$				135	A
Forward On Voltage	$V_{SD}$	$T_J=25^{\circ}\text{C}, I_{SD}=45\text{A}, V_{GS}=0\text{V}$		1.0	1.2	V
Reverse Recovery Time	$t_{rr}$	$T_J=25^{\circ}\text{C}, I_F=23\text{A},$ $di/dt=100\text{A}/\mu\text{s}$		173		nS
Reverse Recovery Charge	$Q_{rr}$			1.13		$\mu\text{C}$
Peak Reverse Recovery Current	$I_{rrm}$			13		A

Notes 1.Repetitive Rating: Pulse width limited by maximum junction temperature

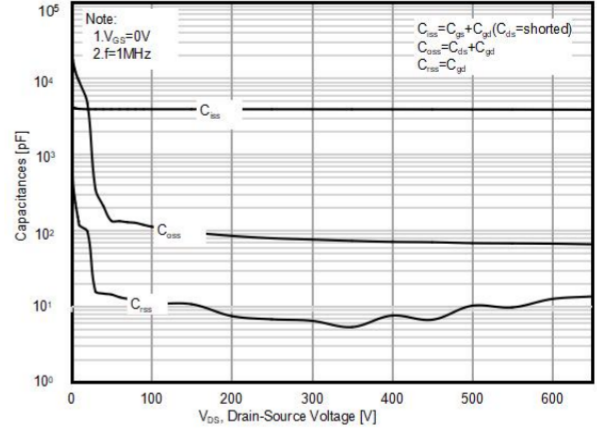
2.  $T_J=25^{\circ}\text{C}, V_{DD}=50\text{V}, V_G=10\text{V}, R_G=25\Omega$

## TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS (curves)

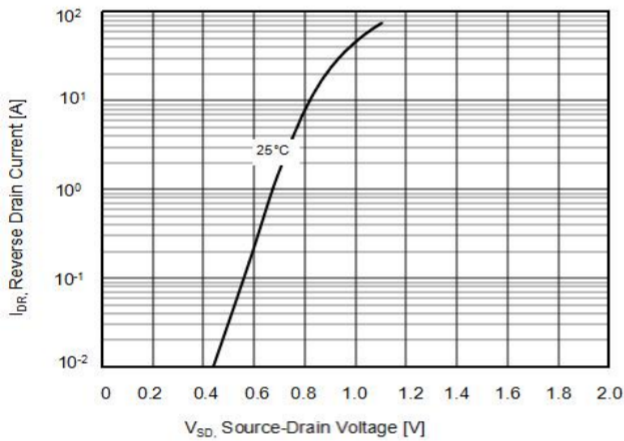
**Figure1. Safe operating area**



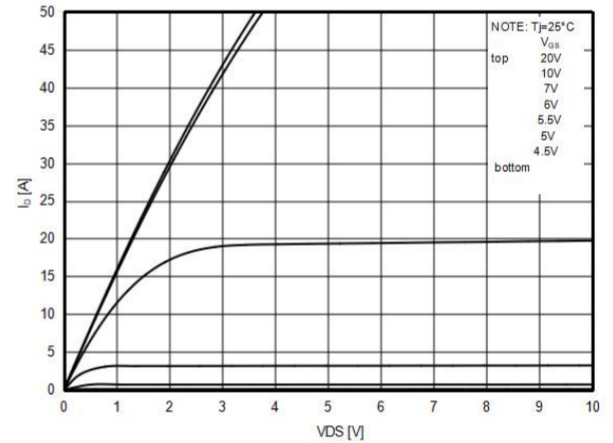
**Figure2. Capacitance**



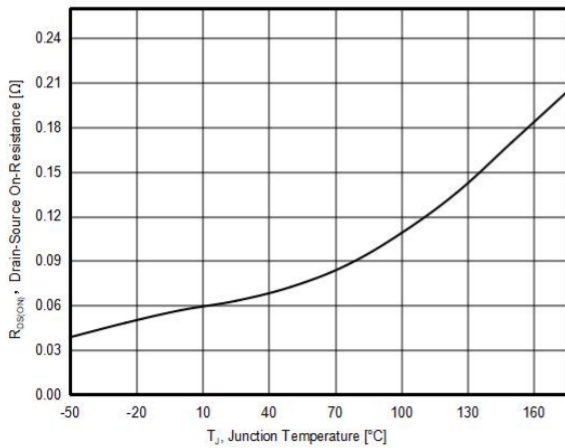
**Figure3. Source-Drain Diode Forward Voltage**



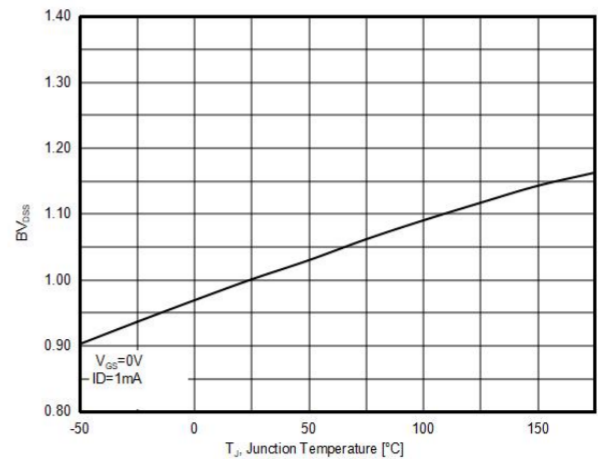
**Figure4. Output characteristics**



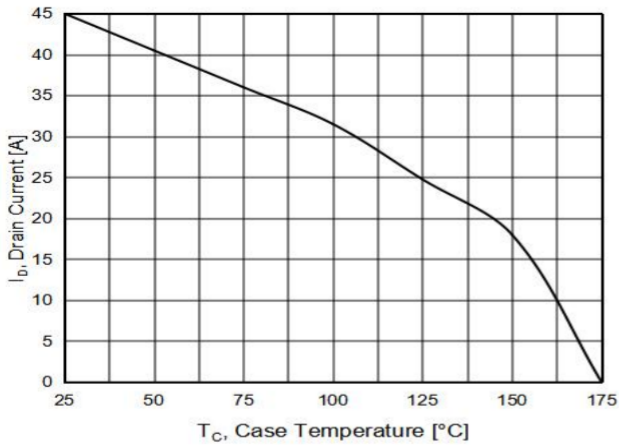
**Figure5.  $R_{DS(ON)}$  vs Junction Temperature**



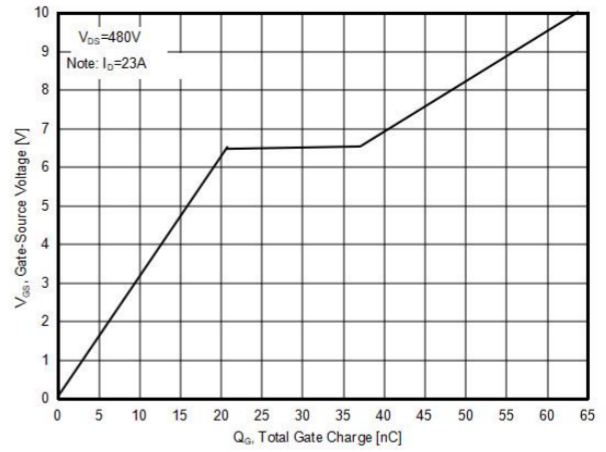
**Figure6.  $BV_{DSS}$  vs Junction Temperature**



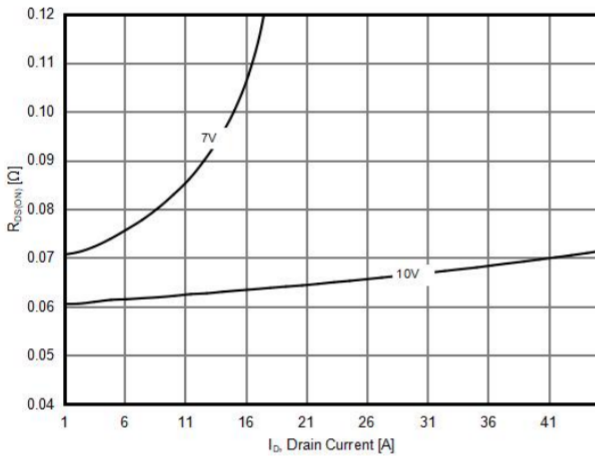
**Figure7. Maximum  $I_D$  vs Junction Temperature**



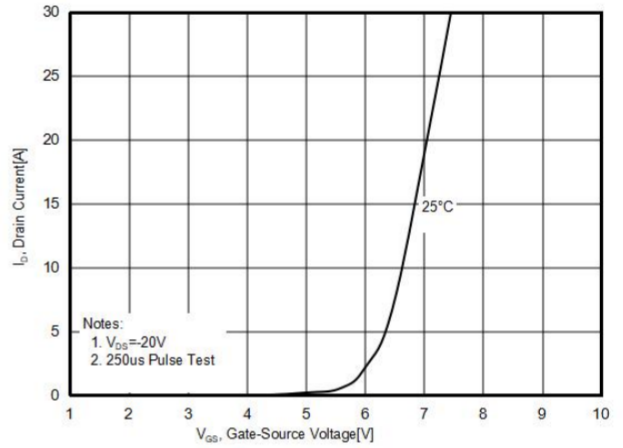
**Figure8. Gate charge waveforms**



**Figure9. Static drain-source on resistance**

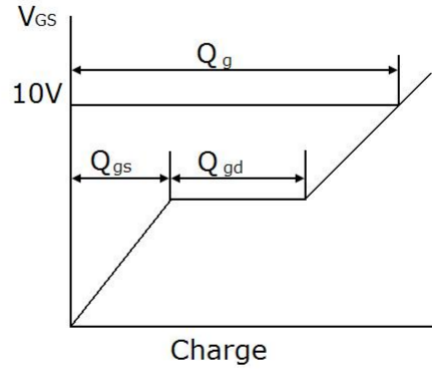
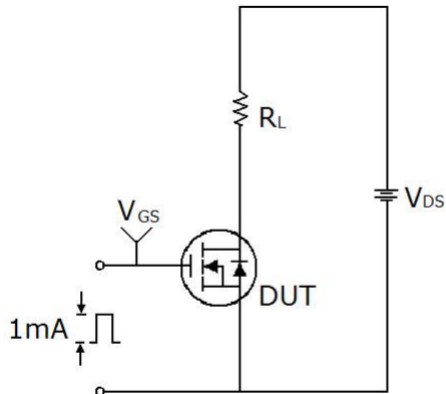


**Figure10. Transfer characteristics**

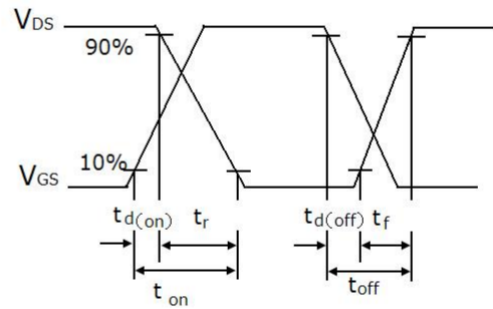
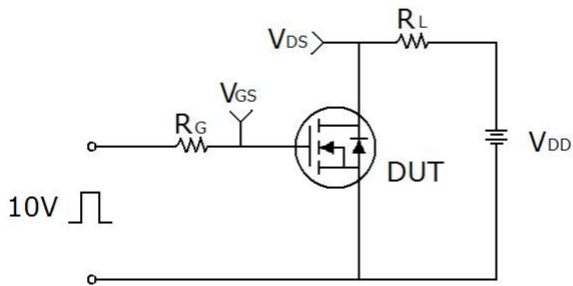


## Test circuit

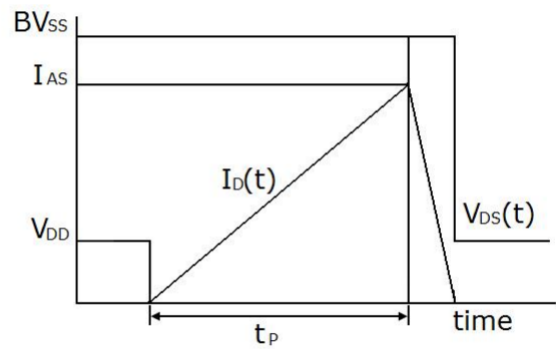
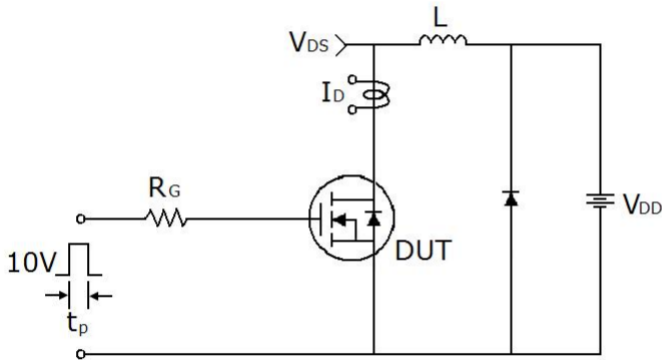
### 1) Gate charge test circuit & Waveform



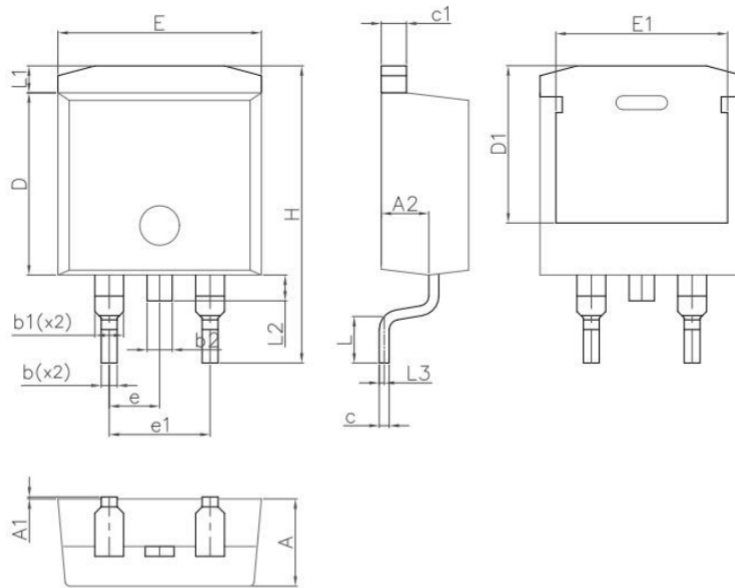
### 2) Switch Time Test Circuit:



### 3) Unclamped Inductive Switching Test Circuit & Waveforms

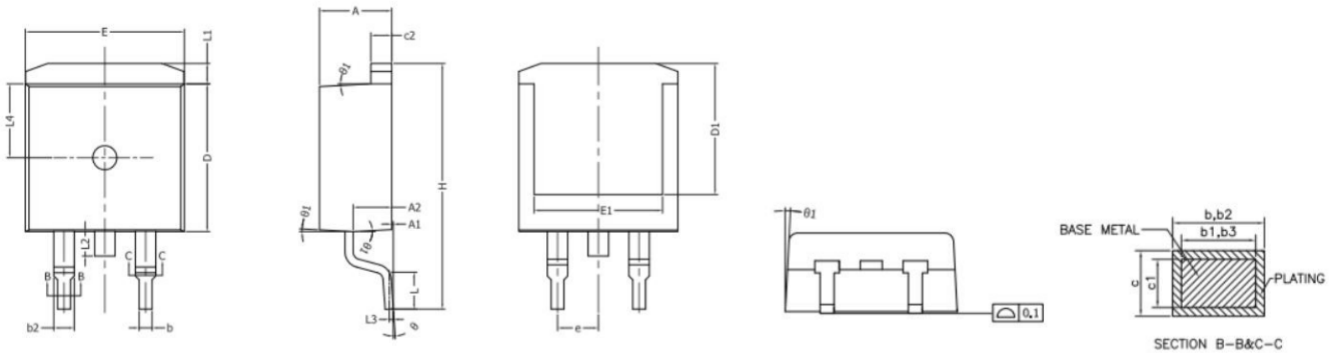


## TO-263-2L-E Package Information



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	4.20	4.60	0.165	0.181
A1	0	0.25	0	0.01
A2	2.20	2.60	0.087	0.102
b	0.70	0.90	0.028	0.035
b1	1.20	1.75	0.047	0.069
b2	1.17	1.37	0.046	0.054
c	0.40	0.60	0.016	0.024
c1	1.15	1.40	0.045	0.055
D	9.10	9.30	0.358	0.366
D1	7.63	8.23	0.300	0.324
E	10.05	10.45	0.396	0.411
E1	8.35	8.95	0.329	0.352
e	2.54BSC		0.100BSC	
e1	5.08BSC		0.200BSC	
H	14.61	15.88	0.575	0.625
L	1.78	2.79	0.070	0.110
L1	1.36REF		0.054REF	
L2	1.30REF		0.051REF	
L3	0.25REF		0.010REF	

## TO-263-2L-J Package Information



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	4.40	4.60	0.173	0.181
A1	0.00	0.25	0.000	0.010
A2	2.20	2.60	0.087	0.102
b	0.76	0.89	0.030	0.035
b1	0.75	0.85	0.030	0.033
b2	1.23	1.37	0.048	0.054
b3	1.22	1.32	0.048	0.052
c	0.47	0.60	0.019	0.024
c1	0.46	0.56	0.018	0.022
c2	1.25	1.35	0.049	0.053
D	9.10	9.30	0.358	0.366
D1	8.00		0.315	
E	9.80	10.00	0.386	0.394
E1	7.80		0.307	
e	2.54BSC		0.100BSC	
H	14.90	15.70	0.587	0.618
L	2.00	2.60	0.079	0.102
L1	1.17	1.40	0.046	0.055
L2		1.75		0.069
L3	0.25BSC		0.101BSC	
L4	4.60REF		0.181REF	
θ	0°	8°		
θ1	1°	5°		

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